

PS401

Single Chip Battery Manager

Features

- Single chip solution for rechargeable battery management
- Embedded Microchip patented Accuron™ technology provides precise capacity reporting (within 1%) for all rechargeable battery chemistries
- User configurable and "learned" parameters stored in on-chip 128 x 8 EEPROM; fully field reprogrammable via SMBus interface
- Integrating sigma-delta A/D converter accurately measures:
	- Current through sense resistor (15-bits)
	- High voltage (18V) battery cells directly connected to VCELL inputs (11-bits)
	- Temperature measurement from on-chip sensor or optional external thermistor (11-bits)
- Integrated precision silicon time base
- Eight individually programmable input/output pins that can be assigned as
	- Charge control I/O
	- Safety function I/O
	- SOC LED output drive pins
	- General purpose I/O
- Full SMBus v1.1 2-wire host interface
- Microchip firmware in 12 Kbytes of customizable on-chip OTP EPROM

Pin Description

Pin Summary

1.0 PRODUCT OVERVIEW

The PS401 is a fully integrated IC for battery management that combines a proprietary microcontroller core together with monitoring/control algorithms and 3D cell models stored in 12 Kbytes of on-chip OTP EPROM. Additional features include: precision 15-bit A/D and mixed signal circuitry. On-chip EEPROM is provided for storage of user-customizable and "learned" battery parameters. An industry standard 2-wire SMBus v1.1 interface supports host communication using standard SBData v1.1 commands and status.

Additional integrated features include an optional, high accuracy on-chip oscillator and temperature sensor. Eight general purpose pins support charge or safety control, SOC LED display or user-programmable digital I/O.

Microchip's PS401 achieves the highest Smart Battery Data accuracy in a single IC, providing space and total system component cost savings for a wide variety of portable systems.

FIGURE 1-1: PS401 INTERNAL BLOCK DIAGRAM

1.1 Architectural Description

Figure 1-1 is an internal block diagram highlighting the major architectural elements described below.

1.2 Microcontroller/Memory

The PS401 incorporates an advanced, low power 8-bit RISC microcontroller core. Memory resources include 12 Kbytes of OTP EPROM for program/data storage, and 128 bytes of EEPROM for parameter storage.

1.3 A/D Converter

The PS401 performs precise measurements of current, voltage and temperature using a highly accurate 15-bit integrating sigma-delta A/D converter. The A/D can be calibrated to eliminate gain and offset errors and incorporates an auto-zero offset correction feature that can be performed while in the end system application.

1.4 Microchip Firmware/Battery Models

Contained within the 12-Kbyte OTP is Microchip developed battery management firmware that incorporates proprietary algorithms and sophisticated 3-dimensional cell models. Developed by battery chemists, the patented, self-learning 3D cell models contain over 250 parameters and compensate for selfdischarge, temperature and other factors. In addition, multiple capacity correction and error reducing functions are performed during charge/discharge cycles to enhance accuracy and improve fuel gauge and charge control performance. As a result, accurate battery capacity reporting and run-time predictions with less than 1% error are readily achievable.

The proprietary algorithms and 3D cell models are contained within the 12-Kbyte on-chip One-Time-Programmable (OTP) EPROM. Firmware upgrades and customized versions can be rapidly created without the need for silicon revisions.

The PS401 can be easily customized for a particular application's battery cell chemistry. Standard configuration files are provided by Microchip for a wide variety of popular rechargeable cells and battery pack configurations.

1.5 SMBus Interface/SBData Commands

Communication with the host is fully compliant with the industry standard Smart Battery System (SBS) Specification. Included is an advanced SMBus communications engine that is compliant with the SMBus v1.1 Packet Error Checking (PEC) CRC-8 error correction protocols. The integrated firmware processes all the revised Smart Battery Data (SBData) v1.1 data values.

1.6 Accurate Integrated Time Base

The PS401 provides a highly accurate RC oscillator that provides accurate timing for self-discharge and capacity calculations and eliminates the need for an external crystal.

1.7 Temperature Sensing

An integrated temperature sensor is provided to minimize component count where the PS401 IC is located in close physical proximity to the battery cells being monitored. As an option, a connection is provided for an external thermistor that can be simultaneously monitored.

1.8 General Purpose I/O

Eight programmable digital input/output pins are provided by the PS401. These pins can be used as LED outputs to display State-Of-Charge (SOC), or for direct control of external charge circuitry, or to provide additional levels of safety in Li Ion packs. Alternatively, they can be used as general purpose input/outputs.

 ²⁰⁰³ Microchip Technology Inc. DS40238B-page 3

TABLE 1-1: PS401 PIN DESCRIPTION

2.0 A/D OPERATION

The PS401 A/D converter measures voltage, current and temperature and integrates the current over time to measure state-of-charge. The voltage of all battery cells and the entire pack is monitored, and the pack and each cell input are individually calibrated for accuracy. Using an external sense resistor, current is monitored during both charge and discharge and is integrated over time using the on-chip oscillator as the time base. Temperature is measured from the on-chip temperature sensor or an optional external thermistor. Current and temperature are also calibrated for accuracy.

2.1 Current Measurement

The A/D input channels for current measurement are the RSHP and RSHN pins. The current is measured using an integrating method, which averages over time to get the current measurement and integrates over time to get a precise measurement value.

A 5 to 600 milli-Ohm sense resistor is connected to RSHP and RSHN as shown in the example schematic. The maximum input voltage at either RSHP or RSHN is +/-150 mV. The sense resistor should be properly sized to accommodate the lowest and highest expected charge and discharge currents, including suspend and/ or standby currents.

Circuit traces from the sense resistor should be as short as practical without significant crossovers or feedthroughs. Failure to use a single ground reference point at the negative side of the sense resistor can significantly degrade current measurement accuracy.

The OTP EPROM value **NullCurr** represents the zerozone current of the battery. This is provided as a calibration guard band for reading zero current. Currents below +/- **NullCurr** (in mA) limit are read as zero and not included in the capacity algorithm calculations. A typical value for **NullCurr** is 3 mA, so currents between -3 mA and +3 mA will be reported as zero and not included in the capacity calculations.

The equation for current measurement resolution and sense resistor selection is:

 9.15 mV / RSENSE (milli-Ohms) = Current LSB (Minimum current measurement if > **NullCurr**) Current LSB x 16384 = Maximum current measurement possible

In-circuit calibration of the current is done using the SMBus interface at time of manufacture to obtain absolute accuracy in addition to high resolution. The current measurement equation is:

I(ma) = (I_A/D – **COCurr** – **COD**) *** CFCurr** /16384

where:

I_A/D is the internal measurement.

COCurr is the "Correction Offset for Current" which compensates for any offset error in current measurement, stored in OTP EPROM.

CFCurr is the "Correction Factor for Current" which compensates for any variances in the actual sense resistance over varying currents, stored in OTP EPROM

Figure 2-1 shows the relationship of the **COCurr** and **CFCurr** values.

FIGURE 2-1: COCurr AND CFCurr

VALUE RELATIONSHIP

2.2 Auto-Offset Compensation

Accuracy drift is prevented using an automatic autozero self-calibration method which 're-zeroes' the current measurement circuit every 30 seconds, when enabled. This feature can correct for drift in temperature during operation. The Auto-Offset Compensation circuit works internally by disconnecting the RSHP and RSHN inputs and internally shorting these inputs to measure the zero input offset. The EEPROM and calibration value COD is the true zero offset value of the particular IC. When an Auto-Offset Compensation measurement occurs (once per 30 seconds), the actual current measurement is skipped and the previous measurement for current is used for the next capacity calculation.

2.3 Voltage Measurements

The A/D input channels for cell and pack voltage measurements are the VC(1) to VC(4) pins. Measurements are taken each measurement period when the A/D is active. The maximum voltage at any VCELLX input pin is 19V absolute, but voltages above 18V are not suggested. The individual cell voltages are measured with an integration method to reduce any sudden spikes or fluctuations. The A/D uses an 11-bit Resolution mode for these measurements.

Only one cell voltage input is read per measurement period, therefore in multi-cell configurations, it may take multiple measurement periods to read all inputs. This could be further extended by the use of Run mode, where A/D measurements are not activated every measurement period, depending on the configuration of **SampleLimit** and **NSample** values. (See Section 3.0, Operational Modes for additional information.) For Li Ion, Li-based or even Lead-Acid applications, up to four (4) series cell voltages may be monitored individually. The highest voltage cell of the stack must be connected to VC(1).

For some applications, the actual cell stack arrangement can be altered accordingly. The PS401 voltage inputs pins (VCELLx pins) are capable of measuring up to 18V each. Therefore, cell arrangements can be combined and the corresponding cell voltage thresholds can be adjusted. For example, a 2-cell Li Ion pack could actually be connected as a single 7.2V cell instead of two 3.6V cells. The values for the cell voltages would all be doubled and only the VC(1) input pin would be used.

Each VCELLx input circuit contains an internal resistive divider to reduce the external voltage input to a range that the internal A/D circuit can accommodate (150 mV maximum). These dividers are set based on a cell voltage range of 4.5 Volts maximum.

The impedance at each VCELLx input is roughly 100 kOhms, but is only connected to ground (via the VSSA pins) when the actual voltage measurement is occurring. This corresponds to an insignificant amount of capacity drained through this circuit during the brief voltage measurement period.

2.3.1 IMPEDANCE COMPENSATION

Since accurate measurement of pack voltage and cell voltages are critical to performance, the voltage measurements can be compensated for any impedance in the power path that might affect the voltage measurements.

The first compensation point is the current sense resistor. This sense resistor affects the measured voltage of the lowest cell in a Li Ion configuration, since the ground reference point for the measurement is on the side of the current sense resistor farthest from the lowest cell.

The OTP EPROM value **PackResistance** is used to compensate for additional resistance that should be removed.

The equation for the compensation value (in ohms) is:

PackResistance = Trace resistance * 65535

(This is a 2-byte value so the largest value is 1 ohm.)

This requires modification of overall voltage SBData function to compensate for pack resistance and shunt resistance of current sense resistor. Thus, the previous voltage equation is modified to:

SBData Voltage value = $VC(1) + Measured$ Current (mA) * **PackResistance** / 65535)

Figure 2-2 illustrates the compensations provided by the **PackResistance** value. The heavy traces are the portions of the circuit represented by the resistance.

The voltage measurement equation is:

$$
V (mV) = (V_A/D - \textbf{COVPack}) \times \textbf{CFVPack} / 2048
$$
 where:

V_A/D is the internal measurement output.

COVPack is the "Correction Offset for Pack Voltage" which compensates for any offset error in voltage measurement (since the offset of the A/D is less than the voltage measurement resolution of +/- 16.5 mV, the COVPack value is typically zero).

FIGURE 2-2: PACK RESISTANCE VALUE COMPENSATIONS

CFVPack is the "Correction Factor for Pack Voltage" which compensates for any variance in the actual A/D response versus an ideal A/D response over varying voltage inputs.

The **COVPack** and **CFVPack** are calibration constants that are stored in EEPROM.

Figure 2-3 shows the relationship of the **COVPack** and **CFVPack** values.

In-circuit calibration of the voltage is done at the time of manufacture to obtain absolute accuracy in addition to high resolution. Accuracy of ±40 mV at zero current and ±80 mV during charge or discharge is possible. Individual cell voltage measurements can be accurate to within ±40 mV.

The individual cell voltage inputs are also calibrated the same way the pack voltage is. There is one offset value **COVCell** for all individual cells and up to four different correction factors **CFVCell1** through **CFVCell4**, one for each cell input.

2.4 Temperature Measurements

The A/D receives input from the internal temperature sensor to measure the temperature. Optionally, an external thermistor can be connected to the VNTC pin which is also monitored by the A/D converter. An output reference voltage for use with an external thermistor is provided on the VREFT pin. The A/D uses an 11-bit Resolution mode for the temperature measurements.

A standard 10 kOhms at 25°C Negative-Temperature-Coefficient (NTC) device of the 103ETB type is suggested for the optional external thermistor. One leg of the NTC should be connected to the VREFT pin and the other to both the VNTC pin and a 3.65 kOhms resistor to analog ground (VSSA). The resistor forms the lower leg of a voltage divider circuit. To maintain high accuracy in temperature measurements, a 1% resistor should be used.

A lookup table is used to convert the voltage measurement seen at the VNTC pin to a temperature value. The external thermistor should be placed as close as possible to the battery cells and should be isolated from any other sources of heat that may affect its operation. An algorithm feature is activated to disable temperature readings for 30 seconds, following an LED switch activation (SWITCH pin is shorted to VDDD) to prevent false temperature readings due to LED heating.

Calibration of the temperature measurements involves a correction factor and an offset exactly like the current and voltage measurements. The internal temperature measurement makes use of correction factor **CFTempI** and offset **COTempI**, while the VNTC and VREFT pins for the optional external thermistor make use of correction factor **CFTempE** and offset **COTempE**.

 ²⁰⁰³ Microchip Technology Inc. DS40238B-page 7

3.0 OPERATIONAL MODES

The PS401 operates on a continuous cycle, as illustrated in Figure 3-1. The frequency of the cycles depends on the Power mode selected. There are three Power modes: Run, Sample and SLEEP. Each mode has specific entry and exit conditions as listed below.

3.1 Run Mode

Whether the PS401 is in Run mode or Sample mode depends on the magnitude of the current. The Run and Sample mode entry-exit threshold is calculated using the following EEPROM data values and formula:

+/- X mA = **SampleLimit x CFCurr** / 16384

SampleLimit is a programmable EEPROM value, and **CFCurr** is an EEPROM value set by calibration.

Entry to Run mode occurs when the current is more than +/- X mA for two consecutive measurements. Run mode may only be exited to Sample mode, not to SLEEP mode. Exit from Run mode to Sample mode occurs when the converted measured current is less than the +/- X mA threshold for two consecutive measurements.

Run mode is the highest power consuming mode. During Run mode, all measurements and calculations occur once per measurement period. Current, voltage and temperature measurements are each made sequentially during every measurement period. Only one cell voltage measurement occurs per measurement period. For Li-based applications, each cell input is measured in turn. For example, in 4-cell Li-based configurations, four measurement periods are required to read all cell input voltages.

3.2 Sample Mode

Entry to Sample mode occurs when the converted measured current is less than +/- **SampleLimit** (EE parameter) two consecutive measurements. Sample mode may be exited to either Run mode or SLEEP mode.

While in Sample mode, measurements of voltage, current and temperature occur only once per **NSample** counts of measurement periods, where **NSample** is a programmable EEPROM value. Calculations of stateof-charge, SMBus requests, etc. still continue at the normal Run mode rate, but measurements only occur once every measurement period x **NSample**. The minimum value for **NSample** is two.

The purpose of Sample mode is to reduce power consumption during periods of inactivity (low rate charge or discharge.) Since the analog-to-digital converter is not active except every **NSample** counts of measurement periods, the overall power consumption is significantly reduced.

Configuration Example:

Measurement period is 500 ms **CFCurr** current calibration factor is 12500 SampleLimit is set to 27 **NSample** is set to 16

Result:

Run/Sample mode entry-exit threshold:

27 x 12500 / 16384 = **+/- 20.6 mA**

During Sample mode, measurements will occur every:

16 measurement periods of 500 mS = **every 8 seconds**

3.3 SLEEP Mode

Entry to SLEEP mode can only occur when the measured pack voltage at VC(1) input is below a preset limit set by the EEPROM value **SleepVPack** (in mV). SLEEP mode may be exited to Run mode, but only when one of the wake-up conditions is satisfied.

If the voltage measured at the VC(1) input is below the **SleepVPack** threshold, but the measured current is above the Sample mode threshold (which maintains Run mode), then SLEEP mode will NOT be entered. SLEEP mode can only be entered from Sample mode.

While in SLEEP mode, no measurements occur and no calculations are made. The fuel gauge display is not operational, no SMBus communications are recognized, and only a wake-up condition will permit an exit from SLEEP mode. SLEEP mode is one of the lowest power consuming modes and is used to conserve battery energy following a complete discharge.

When in the SLEEP mode (entry due to low voltage and Sample mode), there are four methods for waking up. They are voltage level, current level, SMBus activity and I/O pin activity. The EEPROM value, **WakeUp**, defines which wake-up functions are enabled, and also the voltage wake-up level. Table 3-1 indicates the appropriate setting. Note that the setting is independent of the number of cells or their configuration.

TABLE 3-1: WakeUp

TABLE 3-2: WakeUp VOLTAGE

TABLE 3-3: POWER OPERATIONAL MODE SUMMARY

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4.0 CAPACITY MONITORING

The PS401 internal CPU uses the voltage, current and temperature data from the A/D converter, along with parameters and cell models from the EEPROM and OTP EPROM, to determine the state of the battery and to process the SBData function instruction set.

By integrating measured current, monitoring voltages and temperature, adjusting for self-discharge and checking for end-of-charge and end-of-discharge conditions, the PS401 creates an accurate fuel gauge under all battery conditions.

4.1 Capacity Calculations

The PS401 calculates state-of-charge and fuel gauging functions using a 'coulomb counting' method, with additional inputs from battery voltage and temperature measurements. By continuously and accurately measuring all the current into and out of the battery cells, along with accurate three dimensional cell models, the PS401 is able to provide run-time accuracy with less than 1% error.

The capacity calculations consider two separate states: charge acceptance or capacity increasing (CI) and discharge or capacity decreasing (CD). The CI state only occurs when a charge current larger than OTP EPROM **NullCurr** value is measured. Otherwise, while at rest and/or while being discharged, the state is CD. Conditions must persist for at least **NChangeState** measurement periods for a valid state change between CD and CI. A minimum value of 2 is suggested for **NChangeState**.

Regardless of the CI or CD state, self-discharge is also calculated and subtracted from the integrated capacity values. Even when charging, there is still a self-discharge occurring in the battery.

To compensate for known system errors in the capacity calculations, a separate error term is also continuously calculated. This term is the basis for the SBData value of MaxError. Two error values are located in OTP EPROM. The **CurrError** value is the inherent error in current measurements and should be set based on the selection of a sense resistor and calibration results. The **SelfDischrgErr** value is the error in the parameter tables for self-discharge and depends on the accuracy of the cell chemistry model for self-discharge.

Since the PS401 electronics also drain current from the battery system, another OTP EPROM value allows even this minor drain to be included in the capacity calculations. The **PwrConsumption** value represents the drain of the IC and associated circuitry, including additional safety monitoring electronics, if present. A typical value of 77 represents the PS401's nominal power consumption of 300 µA.

The total capacity added or subtracted from the battery (change in charge) per measurement period is expressed by the following formula:

 Δ Charge = $\Sigma i \Delta t$ (the current integrated over time)

- **CurrError** (Current Meas. Error)
- **PwrConsumption** * ∆t (PS401 IDD)
- % of Self-Discharge * FCC
- **SelfDischrgErr** (Self-Disch. Error)

The error terms are always subtracted, even though they are +/- errors, so that the fuel gauge value will never be overestimated. Current draw of the PS401 and the self-discharge terms are also always subtracted. The SBData value MaxError is the total accumulated error as the gas gauge is running.

The battery current will be precisely measured and integrated at all times and for any current rate, in order to calculate total charge removed from or added to the battery. Based on lookup table access, the capacity is adjusted with self-discharging rates depending on actual capacity and temperature, and residual capacity corrections depending on the discharging current rate and temperature.

4.2 Discharge Termination and Capacity Relearn

Discharge capacity is determined based on the End-Of-Discharge (EOD) voltage point. This voltage can be reached at different times based on the discharge rate. The voltage level at which this point occurs will also change depending on the temperature and discharge rate, since these factors affect the voltage curve and total capacity of the battery. The EOD voltage parameter table predicts the voltage point at which this EOD will be reached based on discharge rate and temperature.

The PS401 will monitor temperature and discharge rate continuously and update the EOD voltage in real-time. When the voltage measured on the cell is below **EOD voltage** for duration of **EODRecheck** x periods, a valid EOD has occurred.

When a valid EOD has been reached, the TERMINATE_DISCHARGE_ALARM bit (bit 11) in BatteryStatus will be set. This will cause an AlarmWarning condition with this bit set.

Additionally, the REMAINING_TIME_ALARM and/or REMAINING_CAPACITY_ALARM bits can be set first to give a user defined early warning prior to the TERMINATE_DISCHARGE_ALARM.

 ²⁰⁰³ Microchip Technology Inc. DS40238B-page 11

To maintain accurate capacity prediction ability, the **FullCapacity** value is relearned on each discharge, which has reached a valid EOD after a previous valid fully charged EOC. If a partial charge occurs before reaching a valid EOD, then no relearn will occur. If the discharge rate at EOD is greater than the 'C-rate' adjusted value in **RelearnCurrLim,** then no relearn will occur.

When a valid EOD has been reached, then the error calculations represented by the SBData value of MaxError will be cleared to zero. If appropriate, the relearned value of **FullCapacity** (and FullChargeCapacity) will also be updated at this time.

4.3 EOD Voltage LookUp Table

4.3.1 SAVE TO DISK POINT

As the graph in Figure 4-1 shows, available capacity in the battery varies with temperature and discharge rate. Since the remaining capacity will vary, the save to disk point of a PC will also vary with temperature and discharge rate.

Knowing the discharge rate that occurs in the system during the save to disk process, and knowing the temperature can pinpoint the exact save to disk point that will always leave the perfect save to disk capacity. The PS401 uses this information to tailor the gas gauge to the system and the remaining capacity and RSOC fuel gauge function will always go to zero at the efficient save to disk point. Table 4-1 will use the voltage points at which this happens as the error correction and FULL CAPACITY relearn point. This will ensure a relearn point before save to disk occurs, and will correct any error in remaining capacity, also to ensure proper save to disk.

The shutdown point has to equal the capacity required to save to disk UNDER THE CONDITIONS OF SAVE TO DISK. That is, looking at the curve that represents the actual discharge C-rate that occurs during the system save to disk function, we must stop discharge and initiate save to disk when the system has used capacity equal to that point on the save to disk C-rate curve. This is because, no matter what the C-rate is when the STD point is reached, the system will automatically switch to the C-rate curve that represents the actual current draw of the save to disk function. So it doesn't matter if the system is in high discharge, or low discharge, it will be in "save-to-disk" discharge conditions when save to disk begins, and there must be enough capacity left.

The graph in Figure 4-1 shows that the system will always shut down at the same capacity point regardless of C-rate conditions (since the C-rate of the save to disk procedure is a constant). Thus, we can automatically have an RSOC that is compensated for C-rate; it will go to zero when the capacity used is equal to the point at which STD occurs.

Ignoring the effects of temperature, we could mark the capacity used up to the shutdown point of the STD curve. All of the shutdown voltage points would then represent the same capacity, and RSOC would always become zero at this capacity, and FCC would always equal this capacity plus the residual capacity of the save to disk curve.

To compensate for temperature, we can look at the series of curves that represent the STD C-rate at different temperatures. The PS401 implementation is to measure the temperature and choose a scaled RSOC value that will go to zero at the save to disk point at this temperature, assuming the temperature does not change. If it does change, then an adjustment to RSOC will be needed to make it go to zero at STD point.

Taking temperature into consideration, the amount of capacity that can be used before save to disk is a constant as C-rate changes, but not constant as temperature changes. Thus, in the LUT, Table 4-1, the individual temperature columns will have voltage points that all represent the same capacity used, but the rows across temperature points (C-rate rows) will represent different capacity used.

FIGURE 4-1: SAVE TO DISK POINT

To compensate RSOC and RM, interpolation will be used and the compensation adjustment can happen in real-time to avoid sudden drops or jumps. Every time the temperature decreases by one degree, a new interpolated value will be subtracted from RSOC and RM. Every time the temperature increases by one degree, RSOC and RM will be held constant until discharged capacity equals the interpolated value that should have been added to RSOC and RM (to avoid capacity increases during discharge). With this

interpolation happening in real-time, there will be no big jumps or extended flat periods as we cross over boundaries in the LUT.

Table 4-1 is an example of the various voltage values that will signal the save to disk points as a function of temperature and discharge rate. Also shown is the amount of capacity used before "save to disk" that will be utilized to compensate RSOC.

Table 4-2 shows the actual names of the values in the OTP EPROM, Table 4-3 shows the value definitions:

	$<$ -10 $^{\circ}$	$<0^{\circ}$	<10°	20	$<30^\circ$	$<40^\circ$	$< 50^\circ$	$<60^\circ$
< 0.2C	V ₁	V ₂	V3	$\overline{}$				
$< 0.5C$								
$< 0.8C$								
$< 1.1C$								
$< 1.4C$								
< 1.7C								
< 2.0C								
$< 2.0 C$						V62	V63	V64
Capacity	20%	10%	5%	3%	0%	0%	0%	0%

TABLE 4-1: V_EOD LOOKUP TABLE

TABLE 4-2: VALUE NAMES IN THE OTP

TABLE 4-3: VALUE DEFINITIONS IN THE OTP EPROM

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5.0 CHARGE CONTROL

A SBS configuration normally allows the Smart Battery to broadcast the ChargingVoltage and Charging-Current values to the Smart Battery Charger (SMBus address 12 HEX) to 'control' when to start charge, stop charge, and when to signal a valid 'fully charged' condition. AlarmWarnings are also sent from the Smart Battery (SMBus address 16 HEX) to the Smart Battery Charger.

Alternately, the SMBus Host or a "Level 3" Smart Battery Charger may simply read the SBData values for ChargingVoltage and ChargingCurrent from the Smart Battery directly. The Host or "Level 3" Smart Battery Charger is also required to read the SBData value of **BatteryStatus** to obtain the appropriate alarm and status bit flags. When used in this configuration, the ChargingCurrent and ChargingVoltage broadcasts can be disabled from the Smart Battery by setting the CHARGER_MODE (bit 14) in the BatteryMode register. The PS401 IC's support all of these functions. (Please refer to the SBS Smart Battery Charger Specification, for a definition of "Level 3" Smart Battery Charger.)

The ChargingCurrent and ChargingVoltage registers contain the maximum charging parameters desired by the particular chemistry, configuration and environmental conditions. The environmental conditions include the measured temperature and the measured cell or pack voltages.

For Li-based systems, ChargingVoltage is the product of the **EOCVolt** and **Cells** values from the EEPROM:

ChargingVoltage = **EOCVolt** x **Cells**

The ChargingCurrent value is set to a maximum using the **ChrgCurr** value from the EEPROM. For lithium systems, both ChargingCurrent and ChargingVoltage values are maximums. When the current reaches **ChrgCurr** it will be held constant at this value. Then when the voltage reaches **ChrgVolt**, the current must be reduced so that the voltage will be constant and not exceed the maximum. This is accomplished by setting ChargingCurrent to **ChrgCurrOff**. For safety reasons, this current change also occurs when the temperature limits are exceeded. When temperature or voltage limits are exceeded, the value of ChargingCurrent changes to **ChrgCurrOff** value from the EEPROM. When a valid End-Of-Charge (EOC) condition is detected and a fully charged state is reached, the ChargingCurrent value is set equal to the **ChrgCurrOff** value.

When ChargingCurrent is set to the **ChrgCurrOff** value, no broadcasts of either ChargingCurrent or ChargingVoltage will occur unless a charge current greater than **NullCurr** is detected by the A/D measurements. Temperature limits are set using the **ChrgMaxTemp**, **DischrgMaxTemp** and **ChrgMinTemp** values from OTP EPROM. These values represent the temperate limits within which ChargingCurrent will be set to **ChrgCurr**. Temperatures outside these limits will cause ChargingCurrent to be set to **ChrgCurrOff.**

If ChargingCurrent is set to **ChrgCurrOff** *and* the measured temperature is greater than **DischrgMaxTemp** *and* less than **ChrgMaxTemp** *and* a charge current is measured which is significantly larger than the **ChrgCurrOff** value, *then* ChargingCurrent will be set to **ChrgCurr** unless a fully charged condition has already been reached.

If the CHARGER_MODE bit in BatteryMode is cleared (enabling broadcasts of ChargingCurrent and ChargingVoltage) then these broadcasts will occur every **NChrgBroadcast** measurement cycles. Broadcasts only occur when ChargingCurrent is set to the **ChrgCurr** value and/or when the A/D converter measures a charge current greater than **NullCurr**.

The Smart Battery Data and Smart Battery Charger Specifications require that ChargingCurrent and ChargingVoltage broadcasts occur no faster than once per 5 seconds and no slower than once per 60 seconds when charging is occurring or desired. This requires that the **NChrgBroadcast** value must be set between 10 and 120. The SMBus Specification also requires that no broadcasts occur during the first 10 seconds after SMBus initialization. This, therefore, requires the **NSilent** value be set to 20 or higher.

Configuration Example:

Results:

ChargingCurrent and ChargingVoltage broadcasts:

100 cycles of 500 msec = every 50 seconds

Broadcast delay after SMBus initialization:

24 cycles of 500 msec = 12 seconds

ChargingCurrent if Temperature > 45°C: **10 mA** ChargingCurrent if Temperature < 0°C: **10 mA** ChargingCurrent if Temperature < 35°C and > 0°C: **2500 mA**

5.1 Full Charge Detection Methods

For a typical lithium ion constant-current/constantvoltage charge system, the PS401 will monitor the taper current that enters the battery once the battery has reached the final voltage level of the charger. Once the taper current falls to a certain level indicating that the battery is full, the End-Of-Charge (EOC) will be triggered. Different taper currents will be used for different temperatures. See the parameter explanation in the programming section for details.

When a valid fully charged EOC condition is detected, the following actions occur:

- The FULLY_CHARGED status bit (bit 5) in the SBData value of **BatteryStatus** is set to one to indicate a full condition. (This will remain set until RelativeStateOfCharge drops below the **ClrFullyChrg** value in OTP EPROM.)
- RelativeStateOfCharge is set to 100%.
- ChargingCurrent is set to **ChrgCurrOff** value.
- SBData value for MaxError is cleared to zero percent (0%).
- The TERMINATE_CHARGE_ALARM bit (bit 14) is set in BatteryStatus and an AlarmWarning broadcast is sent to the SMBus Host and Smart Battery Charger addresses.
- The **OverChrg** value is incremented for any charge received above 100% after a valid fully charged EOC condition.
- Control flags for internal operations are set to indicate a valid full charge condition was achieved.
- Other BatteryStatus or AlarmWarning flag bits may also be set depending on the conditions causing the EOC.

5.2 Temperature Algorithms

The PS401 SMBus Smart Battery IC provides multiple temperature alarm set points and charging conditions. The following EEPROM and OTP EPROM parameters control how the temperature alarms and charging conditions operate.

HighTempAl: When the measured temperature is greater than **HighTempAl**, the Over_Temp_Alarm is set. If the battery is charging, then the Terminate_Charge_Alarm is also set.

ChrgMinTemp, DischrgMaxTemp and ChrgMaxTemp: If the measured temperature is less than ChrgMinTemp, the ChargingCurrent is set to ChrgCurrOff and the ChargingVoltage is set to ChrgVolt to communicate to the charger that the non-charging state of current and voltage should be given. When measured temperature is greater than ChrgMaxTemp and the system is charging, or greater than DischrgMaxTemp and the system is discharging, then ChargingCurrent is set to ChrgCurrOff and the ChargingVoltage is set to ChrgVoltOff also. Otherwise ChargingCurrent = ChrgCurr and ChargingVoltage = ChrgVolt.

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6.0 GPIO CONFIGURATION

6.1 Safety Condition Programming

GPIO0-**GPIO7** are eight 16-bit OTP parameters that are programmed to configure the safety or charge condition desired for their associated pins. **GPIO5** and **GPIO6** must be programmed to configure the desired safety features described below.

There are 8 different functions that can be AND'ed and OR'd together for secondary safety. In **GPIO0**-**GPIO7**, the lower 8-bits are the AND bits and the upper 8-bits are the OR bits. The bits correspond to the secondary safety function as listed in Table 6-1.

The logic selected operates as follows:

AND byte

Desired trigger conditions are selected with a '1' in the control bit. All selected conditions must be true for a true "AND" condition. If no conditions are desired, 0FFh must be written to the byte.

OR byte

Desired trigger conditions are selected with a '1' in the control bit. Any selected condition which is true will cause a true "OR" condition. If no conditions are desired, 00h must be written to the byte. GPIOx pin activation results when all "AND" condition OR any "OR" condition is true.

Example:

If _AND byte is set to 088h, and _OR byte is set to 010h, then the OUTPUTx pin is active only if:

[(*VCELLx* > *VCELL_MAX*) **AND** (*Temperature* > *TEMP_MAX*)] **OR** [*VPACK* > *VPACK_MAX*]

TABLE 6-1: GPIO SAFETY CONDITIONS

TABLE 6-2: GPIO CHARGE CONDITIONS

7.0 SMBus/SBData INTERFACE

The PS401 uses a two-pin System Management Bus (SMBus) protocol to communicate to the Host. One pin is the clock and one is the data. The SMBus port responds to all commands in the Smart Battery Data Specification (SBData). To receive information about the battery, the Host sends the appropriate commands to the SMBus port. Certain alarms, warnings and charging information may be sent to the Host by the PS401 automatically. The SMBus protocol is explained in this chapter. The SBData command set is summarized in Table 7-1.

The PS401 SMBus communications port is fully compliant with the System Management Bus Specification, Version 1.1 and supports all previous and new requirements, including bus time-outs (both slave and master), multi-master arbitration, collision detection/ recovery and PEC (CRC-8) error checking. The SMBus port serves as a Slave for both read and write functions, as well as a Master for write word functions. SMBus slave protocols supported include Read Word, Write Word, Read Block and Write Block, all with or without PEC (CRC-8) error correction. Master mode supports Write Word protocols. The PS401 meets and exceeds the Smart Battery Data Specification, Version 1.1/1.1a requirements. The PS401 is compliant with System Management Bus Specification 1.0.

The PS401 fully implements the Smart Battery Data (SBData) Specification v1.1. The SBData Specification defines the interface and data reporting mechanism for an SBS compliant Smart Battery. It defines a consistent set of battery data to be used by a power management system to improve battery life and system run-time, while providing the user with accurate information. This is accomplished by incorporating fixed, measured, calculated and predicted values, along with charging and alarm messages, with a simple communications mechanism between a Host system, Smart Batteries and a Smart Charger.

The PS401 provides full implementation of the SBData set with complete execution of all the data functions, including sub-functions and control bits and flags, compliance to the accuracy and granularity associated with particular data values, and proper SMBus protocols and timing.

7.1 SBData Function Description

The following subsections document the detailed operation of all of the individual SBData commands.

7.1.1 ManufacturerAccess (0x00)

Reports internal software version when read, opens EEPROM for programming when written with the password.

7.1.2 RemainingCapacityAlarm (0x01)

Sets or reads the low capacity alarm value. Whenever the remaining capacity falls below the low capacity alarm value, the Smart Battery sends alarm warning messages to the SMBus Host with the REMAINING_CAPACITY_ALARM bit set. A low capacity alarm value of '0' disables this alarm.

7.1.3 RemainingTimeAlarm (0x02)

Sets or reads the remaining time alarm value. Whenever the AverageTimeToEmpty falls below the remaining time value, the Smart Battery sends alarm warning messages to the SMBus Host with the REMAINING_TIME_ALARM bit set. A remaining time value of '0' disables this alarm.

7.1.4 BatteryMode (0x03)

This function selects the various Battery Operational modes and reports the battery's capabilities, modes and condition.

Bit 0: INTERNAL_CHARGE_CONTROLLER

Bit set indicates that the battery pack contains its own internal charge controller. When the bit is set, this optional function is supported and the CHARGE_ CONTROLLER_ENABLED bit will be activated.

Bit 1: PRIMARY_BATTERY_SUPPORT

Bit set indicates that the battery pack has the ability to act as either the primary or secondary battery in a system. When the bit is set, this optional function is supported and the PRIMARY_BATTERY bit will be activated.

Bit 2-6: Reserved

Bit 7: CONDITION_FLAG

Bit set indicates that the battery is requesting a conditioning cycle. This typically will consist of a full charge to full discharge back to full charge of the pack. The battery will clear this flag after it detects that a conditioning cycle has been completed.

Bit 8: CHARGE_CONTROLLER_ENABLED

Bit is set to enable the battery pack's internal charge controller. When this bit is cleared, the internal charge controller is disabled (default). This bit is active only when the INTERNAL_CHARGE_CONTROLLER bit is set.

Bit 9: PRIMARY_BATTERY

Bit is set to enable a battery to operate as the primary battery in a system. When this bit is cleared, the battery operates in a secondary role (default). This bit is active only when the PRIMARY_BATTERY_SUPPORT bit is set.

TABLE 7-1: SMART BATTERY DATA FUNCTIONS

Note 1: Reports internal software version when read, opens EEPROM (and selected other values) for programming when written.

Bit 10-13: Reserved

Bit 14: CHARGER_MODE

Enables or disables the Smart Battery's transmission of ChargingCurrent and ChargingVoltage messages to the Smart Battery Charger. When set, the Smart Battery will NOT transmit ChargingCurrent and ChargingVoltage values to the charger. When cleared, the Smart Battery will transmit the ChargingCurrent and ChargingVoltage values to the charger when charging is desired.

Bit 15: CAPACITY_MODE

Indicates if capacity information will be reported in mA/mAh or 10 mW/10 mWh. When set, the capacity information will be reported in 10 mW/10 mWh. When cleared, the capacity information will be reported in mA/mAh.

7.1.5 AtRate (0x04)

AtRate is a value of current or power that is used by three other functions: AtRateTimeToFull, AtRateTimeToEmpty and AtRateOK.

- AtRateTimeToFull returns the predicted time to full charge at the AtRate value of charge current.
- AtRateTimeToEmpty function returns the predicted operating time at the AtRate value of discharge current.
- AtRateOK function returns a Boolean value that predicts the battery's ability to supply the AtRate value of additional discharge current for 10 seconds.

7.1.6 AtRateTimeToFull (0x05)

Returns the predicted remaining time to fully charge the battery at the AtRate value (mA). The AtRateTimeTo Full function is part of a two-function call set used to determine the predicted remaining charge time at the AtRate value in mA. It will be used immediately after the SMBus Host sets the AtRate value.

7.1.7 AtRateTimeToEmpty (0x06)

Returns the predicted remaining operating time if the battery is discharged at the **AtRate** value. The AtRateTimeToEmpty function is part of a two-function call set used to determine the remaining operating time at the **AtRate** value. It will be used immediately after the SMBus Host sets the AtRate value.

7.1.8 AtRateOK (0x07)

Returns a Boolean value that indicates whether or not the battery can deliver the **AtRate** value of additional energy for 10 seconds (Boolean). If the AtRate value is zero or positive, the AtRateOK function will ALWAYS return true. The **AtRateOK** function is part of a two-function call set used by power management systems to determine if the battery can safely supply enough energy for an additional load. It will be used immediately after the SMBus Host sets the AtRate value.

7.1.9 Temperature (0x08)

Returns the cell pack's internal temperature in units of 0.1°K.

7.1.10 Voltage (0x09)

Returns the pack voltage (mV).

7.1.11 Current (0x0a)

Returns the current being supplied (or accepted) through the battery's terminals (mA).

7.1.12 AverageCurrent (0x0b)

Returns a one-minute rolling average based on at least 60 samples of the current being supplied (or accepted) through the battery's terminals (mA).

7.1.13 MaxError (0x0c)

Returns the expected margin of error (%) in the stateof-charge calculation. For example, when MaxError returns 10% and RelativeStateOfCharge returns 50%, the RelativeStateOfCharge is actually between 50% and 60%. The MaxError of a battery is expected to increase until the Smart Battery identifies a condition that will give it higher confidence in its own accuracy. For example, when a Smart Battery senses that it has been fully charged from a fully discharged state, it may use that information to reset or partially reset MaxError. The Smart Battery can signal when MaxError has become too high by setting the CONDITION_FLAG bit in BatteryMode.

7.1.14 RelativeStateOfCharge (0x0d)

Returns the predicted remaining battery capacity expressed as a percentage of FullChargeCapacity (%).

7.1.15 AbsoluteStateOfCharge (0x0e)

Returns the predicted remaining battery capacity expressed as a percentage of DesignCapacity (%). Note that AbsoluteStateOfCharge can return values greater than 100%.

7.1.16 RemainingCapacity (0x0f)

Returns the predicted remaining battery capacity. The RemainingCapacity value is expressed in either current (mAh) or power (10 mWh), depending on the setting of the BatteryMode's CAPACITY_MODE bit.

7.1.17 FullChargeCapacity (0x10)

Returns the predicted pack capacity when it is fully charged. It is based on either current or power, depending on the setting of the BatteryMode's CAPACITY_MODE bit.

7.1.18 RunTimeToEmpty (0x11)

Returns the predicted remaining battery life at the present rate of discharge (minutes). The RunTime-ToEmpty value is calculated based on either current or power, depending on the setting of the BatteryMode's CAPACITY_MODE bit. This is an important distinction because use of the wrong Calculation mode may result in inaccurate return values.

7.1.19 AverageTimeToEmpty (0x12)

Returns a one-minute rolling average of the predicted remaining battery life (minutes). The AverageTime-ToEmpty value is calculated based on either current or power, depending on the setting of the BatteryMode's CAPACITY_MODE bit. This is an important distinction because use of the wrong Calculation mode may result in inaccurate return values.

7.1.20 AverageTimeToFull (0x13)

Returns a one-minute rolling average of the predicted remaining time until the Smart Battery reaches full charge (minutes).

7.1.21 ChargingCurrent (0x14)

Sets the maximum charging current for the Smart Charger to charge the battery. This can be written to the Smart Charger from the Smart Battery, or requested by the Smart Charger from the battery.

7.1.22 ChargingVoltage (0x15)

Sets the maximum charging voltage for the Smart Charger to charge the battery. This can be written to the Smart Charger from the Smart Battery, or requested by the Smart Charger from the battery.

7.1.23 BatteryStatus (0x16)

Returns the Smart Battery's status word (flags). Some of the **BatteryStatus** flags, like REMAINING CAPACITY_ALARM and REMAINING_TIME_ALARM, are calculated based on either current or power, depending on the setting of the BatteryMode's CAPACITY_MODE bit. This is important because use of the wrong Calculation mode may result in an inaccurate alarm. The **BatteryStatus** function is used by the power management system to get alarm and status bits, as well as error codes from the Smart Battery. This is basically the same information returned by the SBData AlarmWarning function, except that the AlarmWarning function sets the Error Code bits all high before sending the data.

Battery Status Bits:

The Host system assumes responsibility for **detecting and responding** to Smart Battery alarms by reading the **BatteryStatus** to determine if any of the alarm bit flags are set. At a minimum, this requires the system to poll the Smart Battery Battery Status every 10 seconds at all times the SMBus is active.

7.1.24 CycleCount (0x17)

CycleCount is updated to keep track of the total usage of the battery. CycleCount is increased whenever an amount of charge has been delivered to, or removed from, the battery equivalent to the full capacity.

7.1.25 DesignCapacity (0x18)

Returns the theoretical capacity of a new pack. The DesignCapacity value is expressed in either current or power, depending on the setting of the BatteryMode's CAPACITY_MODE bit.

7.1.26 DesignVoltage (0x19)

Returns the theoretical voltage of a new pack (mV).

7.1.27 SpecificationInfo (0x1a)

Returns the version number of the Smart Battery specification the battery pack supports.

7.1.28 ManufactureDate (0x1b)

This function returns the date the cell pack was manufactured in a packed integer. The date is packed in the following fashion: (year-1980) * 512 + month * 32 + day.

7.1.29 SerialNumber (0x1c)

This function is used to return a serial number. This number, when combined with the ManufacturerName, the **DeviceName** and the **ManufactureDate** will uniquely identify the battery.

7.1.30 ManufacturerName (0x20)

This function returns a character array containing the battery manufacturer's name.

7.1.31 DeviceName (0x21)

This function returns a character string that contains the battery's name.

7.1.32 DeviceChemistry (0x22)

This function returns a character string that contains the battery's chemistry. For example, if the DeviceChemistry function returns "NiMH," the battery pack would contain nickel metal hydride cells. The following is a partial list of chemistries and their expected abbreviations. These abbreviations are NOT case sensitive.

Lead Acid: PbAc Lithium Ion: LION Nickel Cadmium: NiCd Nickel Metal Hydride: NiMH Nickel Zinc: NiZn Rechargeable Alkaline-Manganese: RAM Zinc Air: ZnAr

7.1.33 ManufacturerData (0x23)

This function allows access to the manufacturer data contained in the battery (data).

7.1.34 OptionalMfgFunction

The PS401 includes new SBData functions using the OptionalMfgFunction command codes. The command codes 3C HEX to 3F HEX report the individual cell voltages as measured by the analog-to-digital converter. These voltages are reported in mV and are calculated to include compensation for calibration and sense resistance voltage drops. Only one cell voltage is measured per measurement cycle (depending on Run or Sample mode operation.)

Rapid voltage changes will see some variation in voltages due to the delay of measurement. These voltage values may be used for cell balancing or other functions as the Host system may desire

TABLE 7-2: PS401 ALARMS AND STATUS SUMMARY

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TABLE 7-3: TEMPERATURE, ChargingCurrent () AND ChargingVoltage () SUMMARY

For all other temperature conditions: ChargingCurrent () = **ChrgCurr** ChargingVoltage () = **ChrgVolt**

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8.0 PARAMETER SETUP

This section documents all of the programmable parameters that are resident in either the OTP EPROM or EEPROM. It includes parameters that are common to the standard PS401 parameter set. The Parameter Set is organized into the following functional groups:

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- 1. Pack Information
- 2. Capacity Calculations
- 3. EOD and FCC Relearn
- 4. Charge Control
- 5. GPIO
- 6. PS401 Settings
- 7. SBData Settings
- 8. Calibration

TABLE 8-1: PACK INFORMATION

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TABLE 8-2: CAPACITY CALCULATIONS (CONTINUED)

Parameter Name	Loc.	# Bytes	Lower Limit	Upper Limit	Typical Value	Operational Description
ADLNearEmpty	EE	1	$\mathbf 0$	255	6	SOC at which A/D switches to emphasize voltage over current measurement near EOD. EE value of $128 = 100\%$.
ADLNearFull	EE	$\mathbf{1}$	Ω	255	122	SOC at which A/D switches to emphasize voltage over current measurement near EOC. EE value of $128 = 100\%$.
EOD1Cap	EE	$\overline{2}$	Ω	65535	$\mathbf 0$	The capacity that remains in the battery at VEOD1. This is typically a small amount used to power a shutdown sequence for the system.
EODRecheck	OTP	$\mathbf{1}$	Ω	255	6	Delay filter for the EOD condition. Number of checks before EOD trigger. The end of discharge conditions must remain for at least this number of periods before being considered true, to help filter out false empty conditions due to spikes.
FullCapacity	EE	$\overline{2}$	$\mathbf 0$	65535	4150	Learned value of battery capacity. Used for SBData value of FullChargeCapacity. This is a learned parameter which is the equivalent of all charge counted from fully charged to fully discharged, including self-discharge and error terms. This is reset after a learning cycle and used for remaining capacity and relative state-of-charge calculations.
NearEODErrReset	OTP	$\overline{2}$	$\mathbf 0$	65535	$\mathbf 0$	Near EOD error RESET.
NearEODRecheck	OTP	$\mathbf{1}$	0	255	6	Number of periods of valid pack voltage measurements needed to trigger near EOD capacity RESET.
RelearnCurrLim	OTP	$\overline{2}$	$\mathbf 0$	65535	6000	Value of measured current that prevents a capacity relearn from occurring when a terminate discharge alarm condition is reached at End-Of-Discharge (EOD). A learning cycle will happen when the battery discharges from fully charged all the way to fully discharged with no charging in between, and the discharge current never exceeds RelearnCurrLim. Example: 3000. A relearn will only occur if current does not exceed 3000 mA.
RelearnLimit	OTP	1	0	255	205	The maximum relearn limit. The maximum percentage that the FULL_CAPACITY can change after a learning cycle, where 255 = 100%.
RelearnMaxErr	OTP	2	0	65535	200	Maximum error for learning FullCapacity. The FULL_CAPACITY will not be learned after a learning cycle if the error is too great.
RelearnVCell	OTP	\overline{c}	0	65535	200	(Unused)
RLCycles	OTP	$\mathbf{1}$	$\mathbf 0$	255	$\overline{2}$	The number of initial cycles without RelearnLimit. The initial number of cycles where RelearnLimit is not active. FullCapacity can vary more greatly with the first learning cycle, since the initial capacity may not be correct, thus this should be set to at least '2'.
VEOD1	EE	\overline{c}	0	65535	3100	First end-of-discharge voltage point. At this point, capacity is set to S_CAP1, and FCC relearn takes place.
VEOD ₂	EE	\overline{c}	0	65535	3000	Second and final end-of-discharge voltage point. At this point, remaining capacity is optionally set to '0'.

TABLE 8-3: EOD AND FCC RELEARN

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TABLE 8-4: CHARGE CONTROL

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TABLE 8-4: CHARGE CONTROL (CONTINUED)

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TABLE 8-5: GPIO (CONTINUED)

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Parameter Name	Loc.	# Bytes	Lower Limit	Upper Limit	Typical Value	Operational Description
AutoOffset	EE	1	Ω	255	60	The frequency of the Auto Offset Calibration cycle.
BlockVersion	OTP	$\overline{2}$	$\mathbf 0$	65535	3	OTP Block ID.
ComOffsetCurr	EE	1	$\mathbf 0$	255	$\overline{7}$	Current offset for Wake-up current level.
ConfigEOC	EE	1	Ω	255	b00010000	Bit coded as follows: Bit Function $\overline{7}$ (free) 6 (free) 5 Limit RemCap to FCC Set overcharge alarm at EOC 4 3 Load capacity with FCC at EOC $\overline{2}$ Trigger EOC on SOC > MaxSOC Trigger EOC on average current 1 Trigger EOC on taper current 0
ConfigEOD	EE	1	Ω	255	b01011000	Bit coded as follows: Bit Function $\overline{7}$ Evaluate EOD1 on fixed voltage (else table) Set fully discharged bit on EOD1 6 5 Set capacity to residual capacity value immediately upon VEOD1 Set Terminate Discharge Alarm on 4 VEOD1 (default on VEOD2) Learn FCC at VEOD1 3 2 TDA alarm at EOD2 Set capacity to zero at VEOD2 1 Do not allow capacity to drop below 0 SCAP

TABLE 8-6: PS401 SETTINGS

TABLE 8-6: PS401 SETTINGS (CONTINUED)

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Name			Limit	Limit	Value	
EEversion	EE	1	0	255		EE version.
FLAGS1	EE	1	0	255	b00100110	Bit coded as follows: Bit Function Enable precharge max current check 7 Hold Charge Current = 0 until next 6 discharge 5 Int/Ext temp Disable SLEEP in main IDLE mode 4 3 Require Run mode for low voltage SLEEP mode \overline{c} Disable safety GPIO 1 Pack resistance enable Enable Run mode detect 0
LUTSelection	EE	1	0	255	b00000000	$b00xxxxx = LUT$ 0 $b01$ xxxxxx = LUT 1 $b10x$ xxxxx = LUT 2 $b11x$ xxxxx = LUT 3 bits 5-0 are unused
NSample	EE	1	$\mathbf 0$	255	10	Frequency of ADC activity in Sample mode. The A/D converter will make measurements every NSample periods while in Sample mode. In Run mode, new measurements are taken every period.
OSCTrim	EE	1	0	255	125	RC oscillator trimming.
PNModeDelay	EE	1	0	255	10	Time slot for Programming mode. When the PS401 is put into Programming mode to program the EEPROM through the SMBus, it will stay in Programming mode for PNModeDelay /2 periods before automatically returning to Normal mode. For $PMModeDelay = 16$, period = 0.5, the PS401 will stay in Programming mode for 8 seconds. EEPROM programming must be finished in this amount of time.
ProgLock	EE	2	0	65535		Code for EEPROM programming function. Determines successful EEPROM update. Internal P4 code only.
PTRActualData	EE.	$\overline{2}$	0	65535	0x1721	OTP starting address of current data block.
RFactor	OTP	1	0	255	$\overline{7}$	C-Rate scaling. RF=28/max C-Rate. This is used to scale all C-rate values, such as taper current values and lookup table C-rates. For a maximum allowable C-rate of 4C in these values, set RF to $28/4 = 7$. By changing RF you can scale all C-rate values in lookup tables and other parameters for use with higher current systems, without changing all the other values.
SampleLimit	EE	$\mathbf{1}$	$\mathbf 0$	255	15	Value used to determine the current threshold for entry/exit for Sample and Run modes: Threshold [mA] = SampleLimit x CfCurr / 16384

TABLE 8-6: PS401 SETTINGS (CONTINUED)

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TABLE 8-6: PS401 SETTINGS (CONTINUED)

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Parameter Name	Loc.	# Bytes	Lower Limit	Upper Limit	Typical Value	Operational Description
BusConfig	EE.	1	0	255	b00100001	Bit coded as follows: Function Bit V2.0 arbitration $\overline{7}$ 6 Master wr w/CRC PEC on 5 4 Baud rate control $2 - 0$ Baud rate 2-0
HighTempAI	EE	2	Ω	65535	750	Over Temp alarm threshold bit in AlarmWarning register, 0.1°C increments, Coded value = (Celsius*10+200). When the temperature exceeds HighTempAlarm, the OverTempAlarm becomes active. If charging, the TerminateChargeAlarm also becomes active.
NChrgBroadcast	EE	$\mathbf{1}$	Ω	255	20	Frequency of charging condition broadcasts.
NSilent	EE	$\mathbf{1}$	0	255	10	Bus-on silence period for messages.
RemCapAl	EE	$\overline{2}$	Ω	65535	440	SBData value for RemCapAl. The SBData specification requires a default of DesignCapacity/10 for this value. When the Remaining Capacity calculation reached the value of RemCapAI, the REMAINING_CAPACITY_ALARM bit will be set in the BatteryStatus register, and an alarm broadcast to the host will occur if alarm broadcasts are enabled.
RemTimeAl	EE	2	Ω	65535	10	SBData value for RemTimeAl. SBData requires a default of 10 minutes for this value. When the RunTimeToEmpty calculation reaches the value of RemTimeAl, the REMAINING_TIME_ALARM bit in BatteryStatus will be set.
SMBusAddr	EE	1	0	255	0x16	SMBus address of the battery.
TCAVolt	EE.	$\overline{2}$	Ω	65535	4500	Cell voltage when the battery sends TERMINATE_CHARGE_ALARM. This is a voltage higher than end-of-charge voltage that will trigger a terminate charge alarm in case EOC is not responded to by the charger.

TABLE 8-7: SBData SETTINGS

TABLE 8-8: CALIBRATION

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Parameter Name	Loc.	# Bytes	Lower Limit	Upper Limit	Typical Value	Operational Description
CFVPack	EE	2	Ω	65535	20045	Correction Factor for Pack Voltage. Adjusts the scaling of the pack voltage measure- ments. Used to calibrate the measurement of pack voltage between VCELL4 input pin and ground.
COCurr	EE	$\mathbf{1}$	-128	127	-12	Correction Offset for Current. This is the value the A/D reads when zero current is flowing through the sense resistor.
COD	EE	$\mathbf{1}$	-128	127	-12	Correction Offset Deviation - Offset value for the auto-zero calibration of the current readings. SBData Current[mA] = (I_A/D - CO_CURR - COD) x CF_CURR / 16384 Calibration: CF_CURR = ((Ammeter[mA] x 16384) - 8192) / (Current - I_A/D at OCV)
COTempE	EE	1	-128	127	-2	Correction Offset for Temperature. Offset $= 0$ used for temperature measurement using internal temperature sensor.
COTempl	EE	2	-32768	32767	-11375	Correction Offset for Temperature. Offset $= 0$ used for temperature measurement using internal temperature sensor.
COVCell	EE	1	-128	127	Ω	Correction Offset for Cell Voltage. Offset factor used for individual cell voltage readings. SBData Voltage[mV] = (V_A/D - CO_VOLT) x CF_VOLT / 2048 Calibration: New CF_VOLT = Old CF_VOLT x (Voltmeter[mV] / SBData Voltage[mV])
COVPack	EE	1	-128	127	$\mathbf 0$	Correction Offset for Voltage. Offset factor used for pack voltage reading.

TABLE 8-8: CALIBRATION (CONTINUED)

9.0 ELECTRICAL CHARACTERISTICS

TABLE 9-1: ABSOLUTE MAXIMUM RATINGS

Note 1: These are stress ratings only. Stress greater than the listed ratings may cause permanent damage to the device. Exposure to absolute maximum ratings for an extended period may affect device reliability. Functional operation is implied only at the listed Operating Conditions below.

TABLE 9-2: DC CHARACTERISTICS (TA = -20°**C TO +85**°**C; VREG (INTERNAL) = +5.0V ±10%)**

Note 1: VREG is the on-chip regulator voltage. It is internally connected to analog supply voltage and is output on the VDDA pin. **2:** Does not include current consumption due to external loading on pins.

3: Sample mode current is specified during an A/D inactive cycle. Sample mode average current can be calculated using the formula: Average Sample mode Supply Current = (IDDRUN + (n-1)*IDDINS)/n; where "n" is the programmed sample rate.

4: During LED illumination, currents may peak at 10mA but average individual LED current is typically 5 mA (using low current, high brightness devices.)

TABLE 9-3: AC CHARACTERISTICS (TA = -20°**C TO +85**°**C; VREG (INTERNAL) = +5.0V ±10%)**

TABLE 9-4: AC CHARACTERISTICS – SMBUS (TA = -20°**C TO +85**°**C; VREG (INTERNAL) = +5.0V ±10%)**

Note 1: Used when broadcasting AlarmWarning, ChargingCurrent and/or ChargingVoltage values to either a SMBus Host or a SMBus Smart Battery Charger. This is only used when the PS401 becomes a SMBus Master for these functions. The receiving (Slave) device may slow the transfer frequency.

2: The PS401 will timeout when the cumulative message time defined from Start-to-Ack, Ack-to-Ack or Ack-to-Stop exceeds the value of tTIMEOUT, Min of 25 ms. The PS401 will reset the communication no later than tTIMEOUT, Max of 35 ms.

- **3:** tHIGH Max provides a simple method for devices to detect bus IDLE conditions.
- **4:** tLOW:SEXT is the cumulative time a slave device is allowed to extend the clock cycles in one message from the initial start to the stop.
- **5:** tLOW:MEXT is the cumulative time a master device is allowed to extend its clock cycles within each byte of a message as defined from Start-to-Ack, Ack-to-Ack or Ack-to-Stop.
- **6:** Rise and fall time is defined as follows:
	- $t = (VIL_{MAX} 0.15)$ to $(VIH_{MIN} + 0.15)$ $tF = 0.9$ VDD to (VIL_{MAX} -0.15)

TABLE 9-5: A/D CONVERTER CHARACTERISTICS (TA = -20°**C TO +85**°**C; VREG (INTERNAL) = +5.0V ±10%)**

Note 1: Voltage is internal at A/D converter inputs. VSR and VNTC are measured directly. VC(x) inputs are measured using internal level-translation circuitry that scales the input voltage range appropriately for the converter.

FIGURE 9-1: SMBus AC TIMING DIAGRAMS

TABLE 9-6: SILICON TIME BASE CHARACTERISTICS (TA = -20°**C TO +85**°**C; VREG (INTERNAL) = +5.0V ± 10%)**

10.0 PACKAGING INFORMATION

28-Lead Plastic Shrink Small Outline (SS) – 209 mil, 5.30 mm (SSOP)

* Controlling Parameter

§ Significant Characteristic

Notes:

Dimensions D and E1 do not include mold flash or protrusions. Mold flash or protrusions shall not exceed .010" (0.254mm) per side. JEDEC Equivalent: MS-150

Drawing No. C04-073

NOTES:

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